

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MICRON: ~~210A~~APPLICATION NO.  
~~18/193,436~~

219C1

10/760,127

INFORMATION DISCLOSURE STATEMENT  
BY APPLICANTAPPLICANT  
Katti, et al.FILING DATE  
~~July 10, 2002~~

1/16/04

GROUP  
~~Unknown~~

2818



SEE SEVERAL SHEETS IF NECESSARY)

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
TN	Daughton, James M., "Advanced MRAM Concepts" <u>Article from NVE Corporation</u> , February 07, 2001, pp. 1-6

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EXAMINER <i>Daughton</i>	DATE CONSIDERED 9/20/2004
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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON 219A <b>219C1</b>	APPLICATION NO. <del>10/193,468</del> <b>10/760,127</b>
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Kati, et al.	
		FILING DATE <del>July 10, 2002</del> <b>1/16/04</b>	GROUP <del>Unknown</del> <b>2818</b>

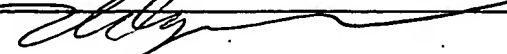
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FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

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TDN	"Magnetoelectronics" [online] [retrieved on January 25, 2002] Retrieved from the Internet: <URL: www.lpm.virginia.edu/research/PVD/Pubs/thesis7/chapter2.PDF> Chapter 2 pp. 7-34
TDN	Everitt, et al., "Pseudo Spin Valve MRAM Cells with Sub-Micrometer Critical Dimension" <i>IEEE Transaction on Magnetics</i> , Vol. 34, No. 4, (1998), pp. 1060-1062
TDN	Lee, et al., "Separation of Contributions to Spin Valve Interlayer Exchange Coupling Field by Temperature Dependent Coupling Field Measurements" [online] 46th MMM Conference Seattle, Washington 2001 pp. 1-16 [retrieved on January 25, 2002] Retrieved from the Internet: <URL:www.andrew.cmu.edu/~zlee/mmm.pdf>
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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. MICRON 218A 219C1	APPLICATION NO. 10/193,458 10/760,127
	APPLICANT Katti, et al.	
	FILING DATE July 10, 2002 1/16/04	GROUP 2818

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TDM	5,541,868	07/30/96	Prinz				
	6,215,695 B1	04/10/01	Ikeda				

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
						YES	NO	

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
TDM	PCT International Search Report dated July 29, 2003
TDM	Inomata, K. "Present and Future of Magnetic RAM Technology" <i>IEICE Transactions on Electronics</i> , Vol. E84-C, No. 6, (June 2001), pp. 740-746

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# Notice of References Cited

Application/Control No.

10/493,458-10/760,127

Applicant(s)/Patent Under  
Reexamination  
KATTI ET AL.

Examiner

Thinh T. Nguyen Unknown

Art Unit

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Page 1 of 1

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	B	US-6,452,764 ✓	09-2002	Abraham et al.	360/324.2
	C	US-2002/0018323 ✓	02-2002	Li et al.	360/314
	D	US-2003/0007398 ✓	01-2003	Daughton et al.	365/200
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	S					
	T					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office  
PTO-892 (Rev. 01-2001)

Notice of References Cited

Part of Paper No. 3

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